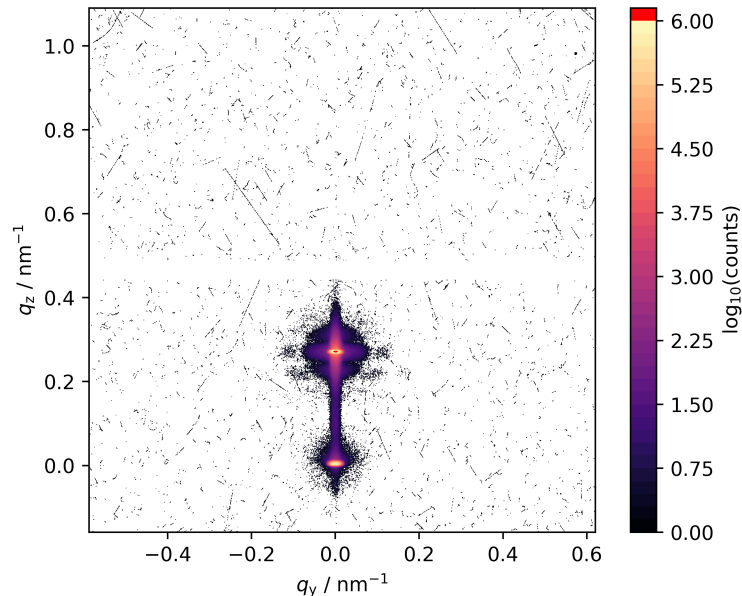


Figure 1: Progression of z , pitch and y scans during automatic sample alignment (steps 1 to 5).



First results from BAM: raw GISAXS counts on polystyrene spheres (nominal diameter: 100 nm) spin-coated onto a Si wafer of 30 mm length. Sample-to-detector distance 2.6 m, incident angle 0.20° , count time 1800 s.